Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/687,643	MINO, TETSUYA
Examiner	Art Unit
Paul D. Kim	3729

	SEARCHED					
Class	Subclass	Date	Examiner			
29	603.11 603.13- 603.16 603.18	7/5/2005	PK			
360	121 122	7/5/2005	PK			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARC))
	DATE	EXMR
Reviewed Parent Application 09/150,206 (US PAT. 6,188,544) 09/734,758 (ABN)	7/5/2005	PK
Textr Search EAST/NPL (IEEE)	7/6/2005	PK
Updated Text Search (EAST)	11/14/2005	PK
Updated Text Search EAST	3/14/2006	PK